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	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Ret
1	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020031012 A1	20020314	26	Method for manufacturing non-volatile memory cell	365/185.26		
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20010015911 A1	20010823	26	Method for operating non-volatile memory cells	365/185.26		
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6353556 B1	20020305	23	Method for operating non-volatile memory cells	365/185.26	365/185.29; 365/185.33	
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6249459 B1	20010619	23	Circuit and method for equalizing erase rate of	365/185.26	365/185.22; 365/185.29	
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6219281 B1	20010417	23	System and method for erasing non-volatile memory	365/185.29	365/185.19; 365/185.33	
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6198662 B1	20010306	23	Circuit and method for pre-erasing/erasing flash	365/185.29	365/185.33; 365/218	
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6166962 A	20001226	23	Circuit and method for conditioning flash memory	365/185.3	365/185.24; 365/185.29	

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	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Ref
1	<input type="checkbox"/>	<input type="checkbox"/>	US 6366519 B1	20020402	16	Regulated reference voltage circuit for flash memory	365/226	363/60	.
2	<input type="checkbox"/>	<input type="checkbox"/>	US 6353556 B1	20020305	23	Method for operating non-volatile memory cells	365/185.26	365/185.29; 365/185.33	
3	<input type="checkbox"/>	<input type="checkbox"/>	US 6249459 B1	20010619	23	Circuit and method for equalizing erase rate of	365/185.26	365/185.22; 365/185.29	
4	<input type="checkbox"/>	<input type="checkbox"/>	US 6023427 A	20000208	16	Voltage pump switch	365/185.33	365/189.02; 365/226;	
5	<input type="checkbox"/>	<input type="checkbox"/>	US 5663907 A	19970902	24	Switch driver circuit for providing small sector sizes	365/185.18	365/185.27	
6	<input type="checkbox"/>	<input type="checkbox"/>	US 5422590 A	19950606	12	High voltage negative charge pump with low voltage CMOS	327/537	327/536; 363/59;	
7	<input type="checkbox"/>	<input type="checkbox"/>	US 5335200 A	19940802	11	High voltage negative charge pump with low voltage CMOS	365/218	327/536; 327/538;	
8	<input type="checkbox"/>	<input type="checkbox"/>	US 5291446 A	19940301	14	VPP power supply having a regulator circuit for	365/189.09	327/540; 365/149;	
9	<input type="checkbox"/>	<input type="checkbox"/>	US 5282170 A	19940125	19	Negative power supply	365/185.33	365/227	

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Feb. 8, 2000

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6,023,427

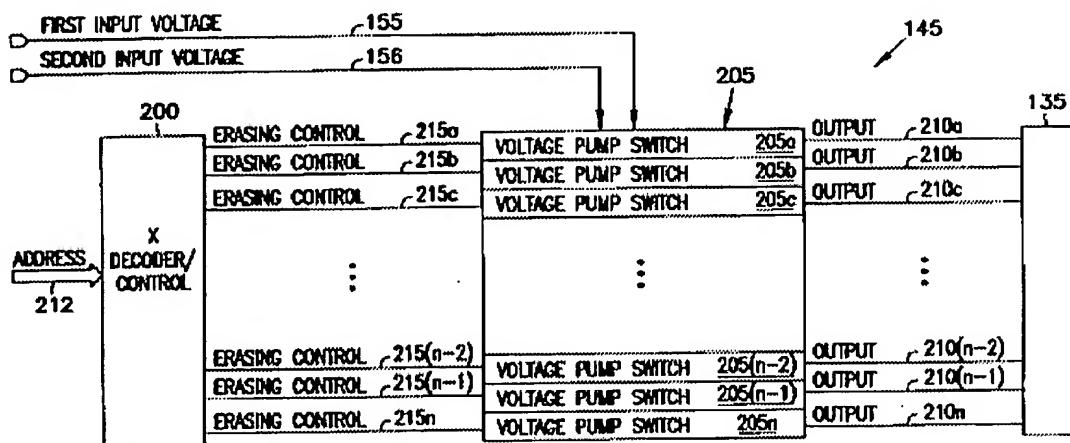


FIG. 2

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U.S. Patent

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6,023,427

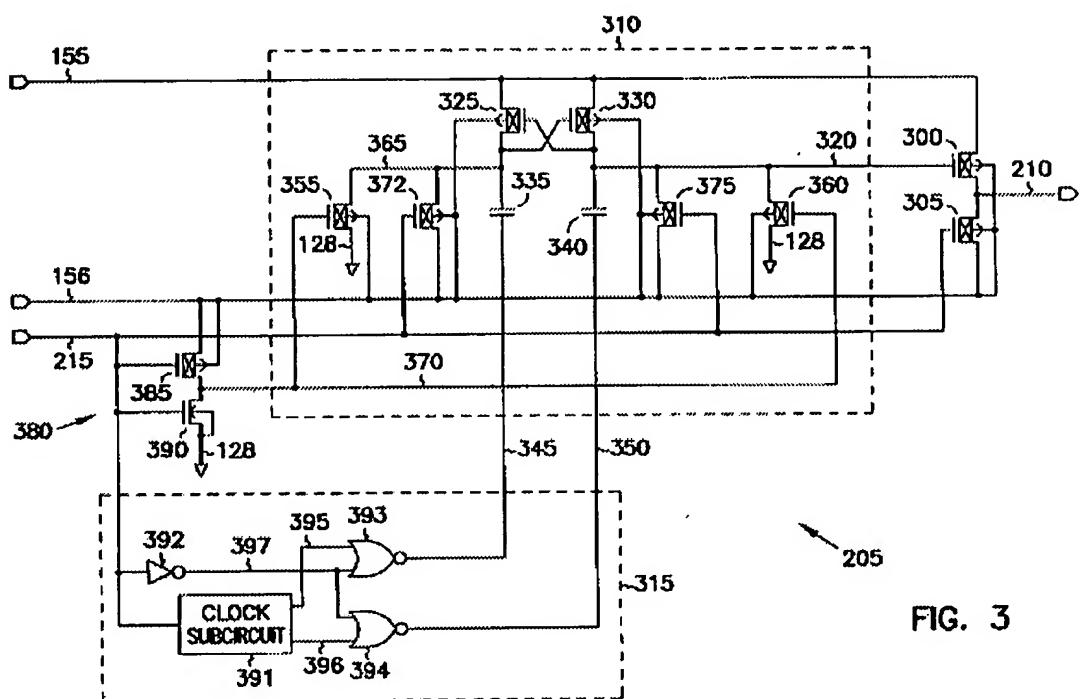


FIG. 3

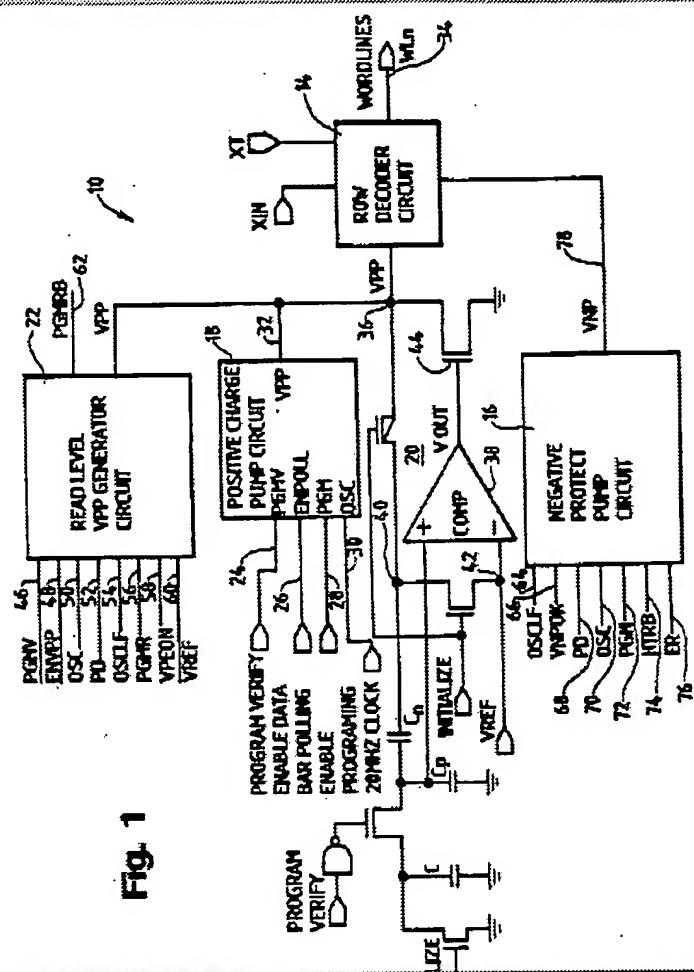


Fig. 1

UNITED STATES PATENT AND TRADEMARK OFFICE

United States Patent [W]

Patent Number: 5,282,170  
Date of Patent: Jun. 23, 1994

**1. INVENTOR:** Michael A. Vea Et al., Inc., Jerry P. Chee, Christopher Clark, L. Christopher, Lee E. Chaudhury, Paul Cava, et al.; City: Ardsley, Minnesota, Raleigh, N.C.

**2. APPLICANT:** Advanced Micro Devices, Inc., Sunnyvale, Calif.

**3. APPL. NO.:** 08/044,627  
**4. FILED:** Oct. 22, 1992  
**5. INT. CL.:** G11C 11/10  
**6. U.S. CL.:** 365/130, 365/131, 365/132, 365/133  
**7. PLAT. OF SEARCH:** 341/23A, 271, 181, 181, 201, 346/21B, 802  
**8. REFERENCES CITED:**

U.S. PATENT DOCUMENTS

1,818,619; 2,785,626; 3,611,702

Priority Drawing—Terry W. Penn  
Assignee Agent or Firm—David Cline

**D7. ABSTRACT:**

A negative power supply for generating and supplying a regulated negative potential to several pins of selected memory cells via wordlines in an array of dual EEPROM memory cells during flash erasure includes charge pump circuit (41) having a plurality of charge pump stages (42) for generating the negative voltage required to each stage of the charge pump source for effectively erasing and threshold voltage steps in the charge pump stages. A regulator circuit (16) responsive to the high negative voltage and a reference potential is provided for generating the regulated negative potential so that it is independent of an external supply potential (VCC).

19 Claims, 8 Drawing Sheets

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